

# Make 3kV C-V Measurements on Power MOSFETs

## Complete Solutions for High Voltage ( $\pm 3kV$ ) C-V Measurements



The 2600-PCT-4B High Power Measurement System

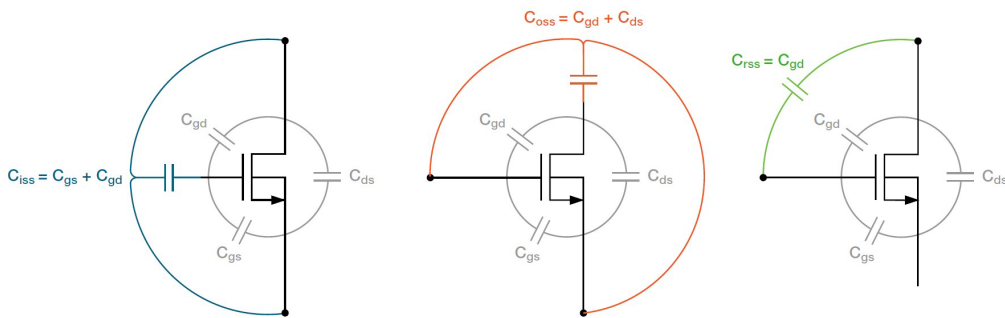
### An Integrated C-V Measurement System

If you need to test power MOSFETs consider a [Keithley Parametric Curve Tracer \(PCT\) system](#) solution for making high voltage C-V measurements. Highlights include:

- $\pm 3kV$  DC Bias
- 1kHz to 1MHz Test Frequency
- pF to  $\mu F$  Capacitance Range
- Bias Tees and Protection Modules
- ACS-BASIC Software that includes compensation and built-in tests for  $C_{oss}$ ,  $C_{iss}$ , and  $C_{rss}$

### Reduce High Voltage C-V Measurement Complexity

The internal capacitance of a power MOSFET affects the switching time and energy loss of the device. Knowing the capacitance of a power MOSFET is important when designing circuitry, so C-V specifications are provided on the device manufacturer's data sheet.



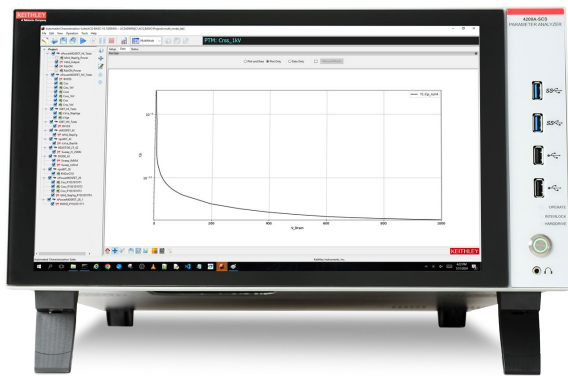
The Component Level Capacitances ( $C_{oss}$ ,  $C_{iss}$ , and  $C_{rss}$ ) of a Power MOSFET

**Complex Test Requirements.** Making high voltage C-V measurements can be difficult. Often commercially available LCR meters are used, but because these are typically rated to 30-40V DC bias, they require a high voltage source or [Source Measure Unit \(SMU\)](#). With the high voltage source in the measurement circuitry, protection modules are additionally needed for the LCR meter or SMU in the event the device breaks down. Bias tees are also required to combine the AC and DC signals to the device. Finally, software is needed to control all the pieces of equipment in the measurement circuit.

# Comprehensive Device-Level Characterization

**Keithley Solution.** To make these measurements easier, Keithley offers a complete solution for making high voltage ( $\pm 3\text{kV}$ ) C-V measurements. Depending on your application, [Keithley PCT systems](#) include the SMUs, CVU, test fixture, cabling, protection modules, and bias tees. This hardware is controlled using the [ACS-BASIC software](#). A 1kV C-V sweep ( $C_{oss}$ ) on a power MOSFET is generated using the PCT system with the ACS-BASIC software (below, right).

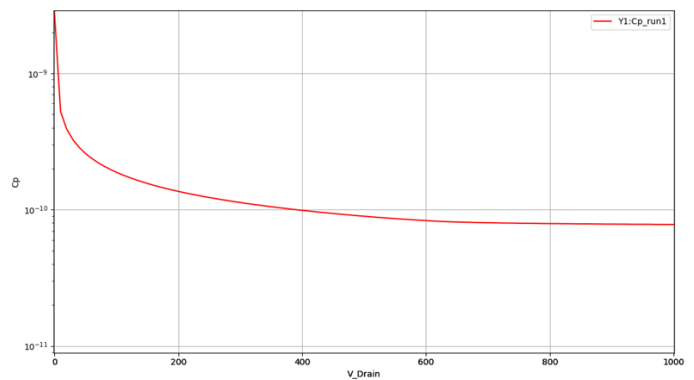
The [Model 2600-PCT-4B High Current and High Voltage PCT Curve Tracer System](#) configuration has both [2651A high current and 2657A high voltage SMUs](#) for making high power I-V measurements. The ACS-BASIC software is installed and executed directly on the [PCT-CVU Capacitance Meter](#) (below, left). The PCT-CVU along with 2657A SMU are used for making the high voltage C-V measurements.



*PCT-CVU Capacitance Meter with ACS-BASIC Software*

## Equipment List for High Voltage C-V

Model	Description
<b>PCT-CVU</b>	Capacitance-Voltage Unit
<b>2600-PCT-3B</b>	High Voltage Curve Tracer incl.: <ul style="list-style-type: none"> <li>• 2657A 3kV SMU (Drain terminal)</li> <li>• 2636B 2-Channel Low Current SMU (Gate and Source terminals)</li> </ul>
<b>CVU-3KV-KIT</b>	Bias Tees
<b>8010</b>	High Power Test Fixture (includes protection modules)
<b>ACS-BASICFL</b>	ACS Basic Edition Control Software (includes library tests for $C_{oss}$ , $C_{iss}$ , and $C_{rss}$ )



*A 1kV C-V Sweep ( $C_{oss}$ ) on a Power MOSFET*

## PCT System Configuration Selector Guide

Model <sup>1, 2</sup>	Collector / Drain Supply <sup>3</sup>		Step Generator Base/Gate Supply	Auxiliary Supply
	High Voltage Mode	High Current Mode		
<b>Low Power</b>	2600-PCT-1B	200 V/10A	200 V/10A	N/A
<b>High Current</b>	2600-PCT-2B	200 V/10A	200 V/10A	200 V/10A
<b>High Voltage</b>	2600-PCT-3B	3 kV/120 mA	200 V/10A	200 V/10A
<b>High Current and High Voltage</b>	2600-PCT-4B	3 kV/120 mA	200 V/10A	200 V/10A

<sup>1</sup> Contact your Keithley field applications engineer for custom configurations.

<sup>2</sup> PCT-CVU Capacitance Meter can be added to any configuration.

<sup>3</sup> Add a Model 2651A SMU to increase high current mode to 50A or 100A.



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